

P404 Power Profiler

The P404 family represents the new generation in a series of high accuracy, cost effective power profiling test solutions from AZ Apps. The P404 is an easy to use, high performance system designed for Engineering, Characterization and Failure Analysis. This new capability will have an immediate impact in improving your product quality and customer satisfaction. By allowing you to duplicate your customer's 'less than perfect' power environment, you can now guarantee your device will function in their products. This powerful and flexible engineering system adds dynamic test and measurement capabilities to the device power pins. Extremely versatile with it's hardware controlled, fully programmable dynamic voltage sources, the P404 also offers unmatched capabilities in Dynamic current measurement. Excel spreadsheet programming virtually eliminates any learning curve. An industry leading visual tool set makes the P404 very valuable addition for your engineering and high volume manufacturing process.

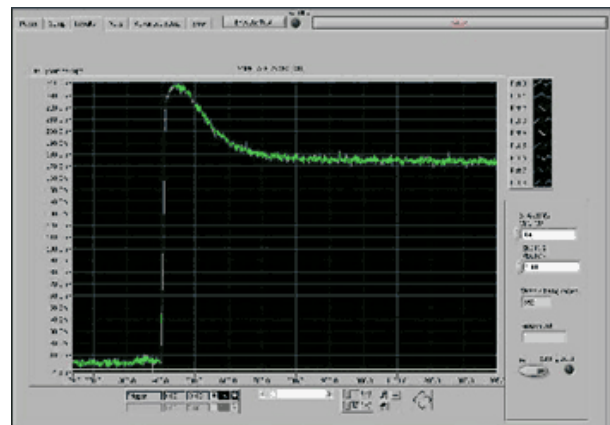
NOTE: For high volume production, P503 provides high throughput, reduced size, power profiling that can be mated to any ATE system. The P503 is easy to install and requires no re-write or changes to your existing test programs and only requires a trigger from the production test system to operate. It adds no additional test time and provides all the data and information you need for fast, accurate power testing on your devices.



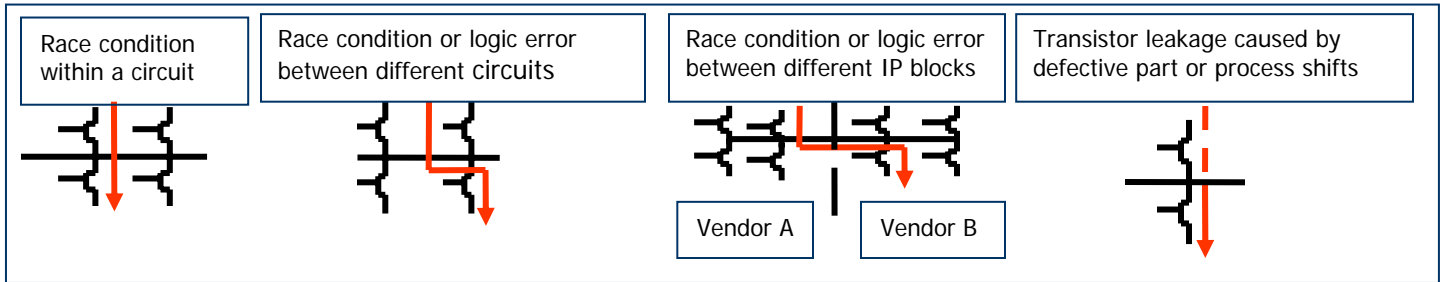
Key Features

for P404 – Engineering and P503 – Production

- Easy to use, non-intrusive addition to existing ATE
- No need to re-write or modify test programs
- 1-12 Fast and accurate/force measure V or I (P404)
- 1-16 Dynamic voltage supplies for sleep, drowsy mode testing
- 1-16 Dynamic IDD measurement units
- Visual results and characterization tools
- Dedicated high accuracy, low impedance active probes
- Excel spreadsheet programming
- Focused tools: i.e. Shmoo, learn mode, etc...



Tested Failure Modes



Capabilities

- Internal mode (Used in most scenarios)
 - Bandwidth = approx 100 MHz
 - Internal current measurement
 - Best for legacy products and test hardware
- High Accuracy Mode (Direct connect to DUT pin)
 - Active external probe
 - Bandwidth = approx 200 MHz
 - X1, X10, X100 Probes
 - No detectable loading from probe
- High Frequency Mode – (Specialized probe connect to DUT pin)
 - Active high frequency dedicated probe
 - Bandwidth = > approx 500 MHz
- VDD modification under vector control
 - State machine functionality
 - Spread sheet programming
- IDD measurements per second
 - A307, P404B = 1 -> 200M
 - P404C, P503, CP1 = 1-> 500M standard
 - P404C, P503, CP1 = 1-> 2G optional
 - Individual I-Limit per measurement
- Data reduction/analysis tools, Database interface
- Graphical displays, Learn modes

